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NATIONAL STANDARD OF THE

PEOPLE'S REPUBLIC OF CHINA

GB/T 6616-1995

Test method for measuring resistivity of semiconductor silicon or sheet resistance of semiconductor films with a noncontact eddy-current gage

半导体硅片电阻率及硅薄膜薄层电阻测定 非接触涡流法

(English Translation)

Issued on: April 18, 1995 **Implemented on: December 1, 1995**

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Table of Contents

Document data

1 Document data

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